

<b>Notice of References Cited</b>	Application/Control No. 10/786,315		Applicant(s)/Patent Under Reexamination IWAKURA ET AL.	
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*	B	US-6,178,539	01-2001	Papadopoulou et al.	716/7
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	V	Hao Shi et al.; "Modeling Multilayered PCB Power-Bus Designs Using an MPIE Based Circuit Extraction Technique", August 1998, IEEE International Symposium on Electromagnetic Compatibility, pages 647 - 651
	W	Frank Y. Yuan, "Electromagnetic Modeling and Signal Integrity Simulation of Power/Ground Networks in High Speed Digital Packages and Printed Circuit Boards", 1998, Proceedings of the 1998 Design Automation Conference, pages 421 - 426
	X	S. Luan et al.; "Extracting CAD Models for Quantifying Noise Coupling between Vias in PCB Layouts", 28 May 2002, Proceedings of the 52nd Electronic Components and Technology Conference, pages 343 - 346

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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